

In the Title:

Insert a new title as follows:

Link Instruction Register Providing Test Control Signals To
Core Wrappers

In the Specification:

[0003] This invention relates generally to testing intellectual property (IP) cores via a test structure called a wrapper. The wrapper resides at the boundary of a core and provides a way to test the core and interconnections between the cores. Particularly, the invention relates to a test architecture for accessing wrappers within an integrated circuit formed on a semiconductor substrate using a Link Instruction Register (LIR). An IEEE P1500 draft standard is in development for providing test access to these individual cores via a test structure called a wrapper. While the IEEE P1500 draft is standardizing test access to the wrapper, it leaves the architectural arrangement for testing multiple and hierarchical wrappers within an IC up to the users of the P1500 standard.